



Call for Papers

12th European Manufacturing Test Conference (EMTC)

20-21 October, Dresden, Germany
In conjunction with SEMICON Europa 2010

<p>“Mapping Digital Test and Diagnosis Approaches on the Emerging Integrated Analog Mixed Signal Arena”</p>
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Continuing in its tradition of providing a practical focus on real solutions in the production test environment, SEMI (Semiconductor Equipment and Materials International) invites European Manufacturing Test professionals to submit abstracts for the European Manufacturing Test Conference which will be held in conjunction with SEMICON Europe 19-21 October 2010 in Dresden, Germany. At the EMTC 2010 we would like to focus on papers that describe practical and successful solutions from the test arena. Taking into account Europe's strength and opportunities, this year's event emphasizes more on the AMS (Analog Mixed Signal) and the RF area.

The EMTC committee would like to address in particular the (smaller) specialized solution companies. Given the dedicated business areas we tend to focus on in Europe, these companies could/should play a key role in Europe.

The main topics we would like to address at the conference include:

- **Performance with a European touch** (Digital and AMS/RF):
 - Test Development Robustness & Industrialization
 - Reducing development time & getting it right the first time
 - Balancing development budgets vs production cost pressures
- **Fab Yield Improvement Through Test Data** (Digital and AMS/RF):
 - The value of test in accelerating Time To Volume / Time To Yield
 - Improving test data reliability / accessibility / utility
- **New Test Challenges**
 - MEMS / High Reliability Devices (such as automotive and healthcare)
 - New Environments / New Challenges / New Requirements
 - Balancing costs vs high quality and performance requirements
 - TSV test and test of systems build with TSV
 - Testing of thinned wafers (<25um)
- **Adaptive Testing**
 - Productivity feed-back loop, in the challenged IC/MST markets
 - What challenges/opportunities does AMS bring in comparison to digital?

- **Board and System Level Testing**
 - Contributions from "system" companies
- **High Speed I/O testing (SERDES, USB, ...) with DfT**
 - Practical experiences using on chip structures to eliminate or reduce the need of high end equipment at volume test

In addition to the focus on hot topics, we also would like to mention the importance of networking during the conference. By enabling enough time for networking, we are sure we all can make the next EMTC into a success. This is even more the case now the conference spreads over an afternoon and the morning, thereby implicitly assigning also the evening for networking (a.o.).

Instructions to submit an abstract – Submit the following information in an e-mail:

- Specify which topic your presentation addresses
- Presentation title
- Abstract of 200-400 words (descriptive paragraph identifying issue addressed and solution)
- Short biography of the author
- Author contact details (Job title, company, address, telephone/e-mail)
- Contact person details i.e. Personal Assistant (Job title, company, address, telephone/e-mail)
- Indicate in subject box of e-mail: EMTC Call for papers

Please submit ALL the above information in one e-mail by 30 April 2010 (extended deadline) to europrograms@semi.org

Your presentation will not be included in the review process unless the information is complete.

Evaluation criteria include significance, usefulness for the manufacturing world and clarity and accuracy as a paper. Abstracts will be peer-reviewed. We encourage operational case studies and application related presentations, i.e. on joint projects between users and suppliers. Papers are to be non-commercial and focus on the technical/economical merits of a process rather than the individual company's product benefits.

Selected presenters will be notified by 28 May 2010.

EMTC Program Committee: Chris Portelli-Hale, STMicroelectronics (co-chair); René Segers (co-chair), Davide Appello, STMicroelectronics, Martin Stadler, Teradyne; Stefan Gasteiger, Advantest; Klaus-Detlef Paesch, Global Foundries; Michael Goldbach, LTX; Roger Barth, Numonyx; Ulrich Schoettmer, Verigy; Stefan Eichenberger, NXP.

For information on SEMICON Europa 2010, please visit www.semi.org/semiconeuropa or contact Carlos Lee, SEMI Europe Tel. +32.2.2896490